

NINETEENTH ANNUAL

**BiTS**

**Burn-in & Test Strategies Workshop** <sup>TM</sup>

**March 4 - 7, 2018**

**Hilton Phoenix / Mesa Hotel  
Mesa, Arizona**

**Archive**

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# Design & Implementation of Universal or Common BIBs Methodology

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**BiTS Workshop**  
**March 4 - 7, 2018**



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## ABSTRACT

- The cost of burn-in boards (BIBs) are a major component of Technology Qualification budget.
- The Cost of BIBs is significantly high due to:
  - Increase in size, density and complexity of the Chips.
  - Higher Voltage & Temperature requirements.
- Dedicated BIBs for each device will be repetitive spending.
- With early planning at TQV\* design, it is possible to design Universal BIBs for at least 2-3 Devices.

\*TQV: Technology Qualification Vehicle

## INTRODUCTION

- Cost of BIBs for EFR\* & HTOL is significantly high.
  - Due to huge sample size for EFR from 3 or more lots
  - Continue to 1000hrs for HTOL qualification.
- Presents different techniques, guidelines or methods
  - For design & implementation of common / UBIBs.
  - That can be used for 2 or more devices.
- Explores on System-wise compatible UBIBs.
- SRAMs are used as example devices for UBIBs.

\*EFR: Early Failure Rate

## Prior Requirements

The Universal/common BIBs, can be designed for different devices.

➤ The devices to satisfy below minimum requirements:

**Same Package:** As sockets on UBIBs will be same, all the devices to have:

- Same package type & number of package pins
- Same Package dimensions (POD\*).

**Same Package Assignments:** Package pin assignments are:

- Known prior to designing of the UBIBs and preferably be same.

\*POD: Package Outline Dimensions

## UBIB Design Guidelines: Power Supplies

### 1. Power Supplies: UBIBs to be designed with

- Maximum number of supply voltages/ PSUs required
- Out of the 2~3 devices that are to be used.
  - Device Power supply needs < PSU's of the UBIBs design.
- Converse is not true:
  - Device that needs more PSU can't use BIBs with less PSU's



## Guidelines – Address & Signals

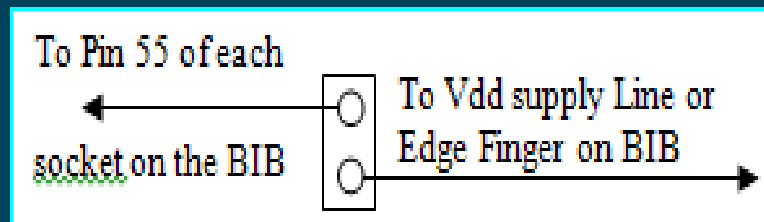
### 2. Address & Signal Lines:

- UBIBs to have maximum number of Channels connected.
- Out of the 2 or 3 devices that are to be used.
- Device Channel needs < # of Channels UBIBs designed for.
- Exchange of Address/Data/Control signals is possible
  - Provided BIB has Scramble Connector Option &
  - Additional signal lines are available.

## 3. Use of Jumper Options -1

### (a) Two Header Jumper Option:

- In case of one of the device pins, need to be floated while others require a connection.
- This is resolved using a two header jumper with either “NC” or “Connect To” for that device.



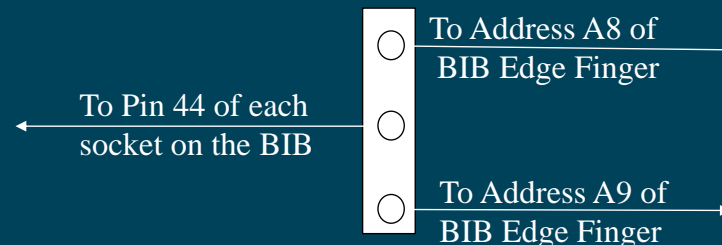
With the above arrangement made, for:

- For Device-1 to float: Keep the Jumper Open.
- For Device-2 to connect to VDD: Short jumper to get connection to Vdd

## Jumper Option - 2

### (b) Three Header Jumper Option:

- One of device pins (supply, IO, Control) requires a different connection Vs other devices.
- This be resolved using a three header jumper option as shown below:

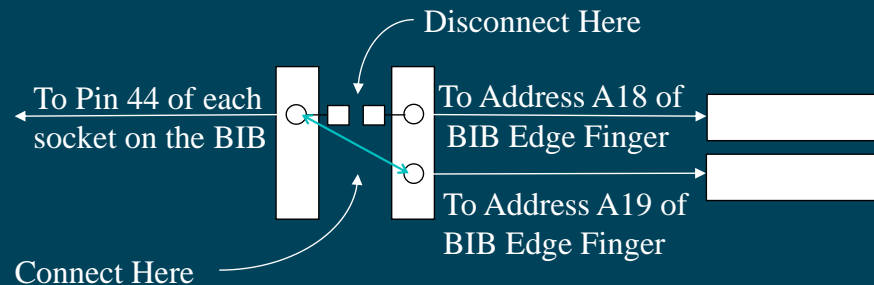


With the above arrangement made:

- To use Device 1: Keep the Jumper Open, which satisfies the condition for that device.
- To use the Device 2: Short Upper Jumper, this gives a connection to “A8” for that device.
- For the Device 3: Short Lower Jumper, which gives a connection to by “A9” for that device.

## Channel Scrambler Option

- 4. Use of Channel Scrambler Option:** To make boards compatible for more device
- It is good practice to have the Scrambler & Pad Connection Option on the UBIBs.
  - Other new devices with same pinouts and satisfies the supply requirements of existing BIBs.



Option can be modified for new devices compatible, requires additional changes on the connections.

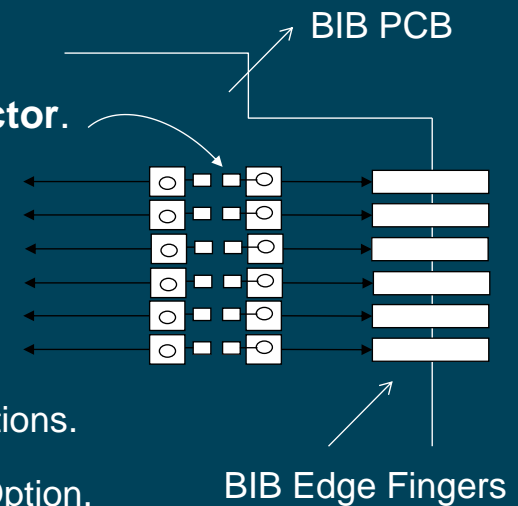
# Scrambler Option Techniques

## UBIB Design to:

- Bring “Un-used channels” from Edge to **Scramble Connector**.
  - To enable boards for new or forthcoming device/s.

Also, Layout “Un-used socket pins” to Scramble Connector.

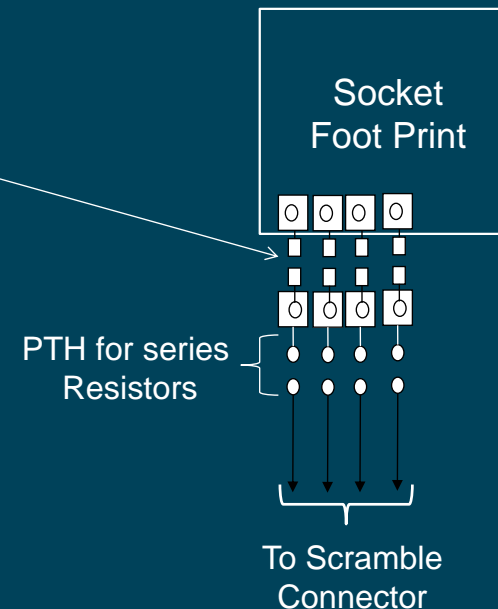
- To enable other or new device/s, to use those additional connections.
- Changes can be made later using the Scramble Connector Option.



## Socket Level Options

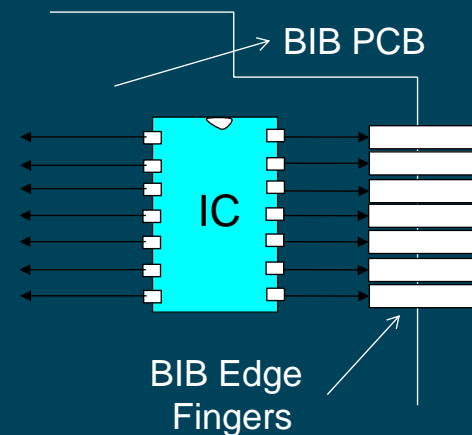
### Socket Level Options:

- All socket pins to have **“Pad-to-Pad Connection”**.
  - Normally shorted by soldering.
- Connect all “no connection” pins to “unused” channels.
  - To use boards for other devices later.
- Also enables UBIBs:
  - To connect or disconnect a pin
  - To change biasing condition of a pin
  - To connect unused channels to new device.



## Other Advanced Options

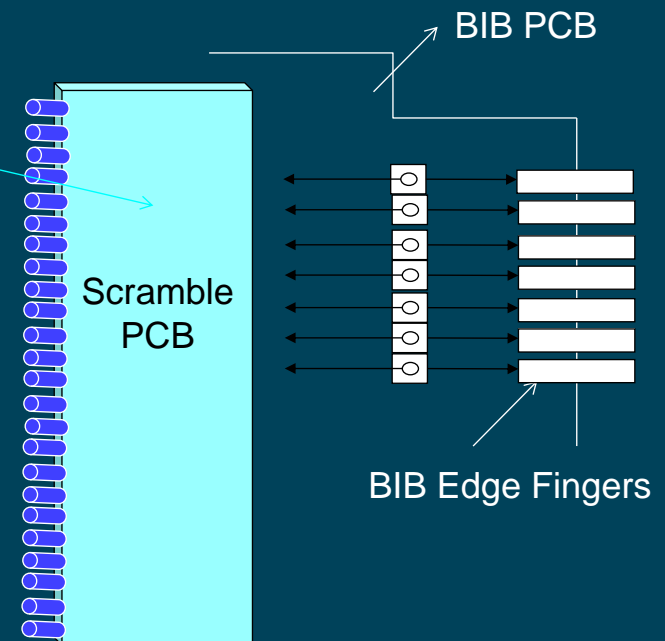
- Include use of ICs on BIBs: Latches, MUX, PAL ICs.
  - Program ICs to select different channels to socket pins.
- BIB layout to implement:
  - Connecting IC Inputs to channels
  - IC output pins to device pins.
- For use of new device, the ICs to be programmed.
- **Pre-caution:** On board ICs to be of high temp. use.
- **Disadvantage:** On Board IC's reduce socket density/BIB.



## Scramble PCB Method

Uses a PCB with all options for new device.

- All the changes will be on a **plug in PCB**.
- Advantageous when:
  - Large number of BIBs need to modify same way.
  - BIBs to be changed between devices too frequently.
  - Changes for different devices are too cumbersome.
- Each device might have unique Scramble PCB.





## System Compatible BIBs & Techniques

- For boards to use on two BI Systems, from same OEM:
  - Number of channels of one Oven is a subset of other.
  - Channel assignments of Edge Connector are same.
- Example Ver-1 (Old) & Ver-2 (New) Systems:
  - a) BIB Edge Connector: 144 Gold Fingers.
  - b) 72 on top, followed by 72 on bottom.

## System Compatible BIBs - 2

Case-1: For Ver-1 boards to use on Ver-2 system:

- Ver-1 with 48 channels, top & bottom fingers shorted.
- Ver-2 with 96 channels, top & bottom fingers open

Above opposing needs are resolved by:

- Channel patterns (PnP) to be modified.
- All channels assigned to bottom 72 fingers to be tri-stated
- A new PnP program to generate per Ver-2 requirements.

**Note:** Ver-1 board on Ver-2 system can only use for a device with 48 channels.

## System Compatible BIBs - 3

Case-2: For Ver-2 board to use on Ver-1 System:

- Ver-2 BIBs designed with 96 channels, top & bottom fingers Open.
  - Devices with 48 channels only can be used on Ver-1 System.
  - New PnP to redevelop per Ver-1 Channel assignments.
  - Edge fingers to short on top & bottom (Option: Scramble PCB)
- Modify test program to use “strobe” and “monitoring” signals.

**Note:** If short is not detected, system may false trigger stimuli fault.

## System Compatible BIBs - 4

Options on Ver-2 BIBs to be compatible (backward) to Ver-1:

- To have shorting Option for top and bottom edge fingers of the BIB

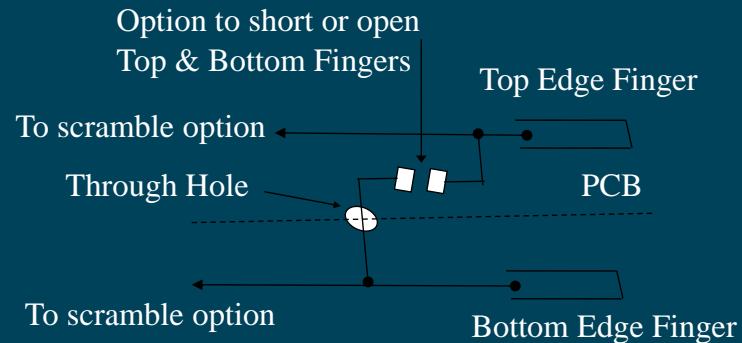
The board design to include:

- A track from each of bottom fingers to a pads next to top fingers.
- All top edge fingers will also be pulled to another set of pads.
- To short the pads to convert BIB back to Ver-1 system compatible.

## System Compatible BIBs - 5

Converse option to design on Ver-1 (old) boards:

- With normally short between top and bottom edge connectors,
- to make them forward compatible to Ver-2 system:
- Removing the short and using a new BI program with Ver-2 requirements.



## Implementation & Cost Savings

**Implementation Done:** Concept used in GF for 3 technology nodes.

- Done by **planning, follow up and design coordination** with:
  - Design Engineering during Device definition phase
  - To plan **same package type** and **Pin assignments** etc.,
  - To ensure **new devices match to existing** UBIBs to use.
- Subsequently same boards were also used for PRMs.

### Estimated Cost Savings:

- For 3 Devices and subsequent tech. nodes Qualifications
- Use UBIBs for PRMs Vs new set of BIBs every time.
- Cost savings are significantly high: **\$0.75~1M** over 3years.

## Cycle Time Savings

**Cycle Time Savings:** Below table shows cycle time savings achieved using UBIBs.

Item	Pre-Project Cycle Time Required	Post-Project Cycle Time Achieved	Cycle Time Saved	Remarks
Boards Re-Fabrication Time	10 wks	1 wk	9 wks	Re-configuration/Minor modifications on the boards.
Boards Re-design & Layout Verification Time	3 wks	0	3 wks	As the redesign and layout verification is eliminated.
Screening Test Program Redevelopment Time	2 wks	0	2 wk	As the redevelopment is eliminated.
Boards Screening Time	1 wk	0	1 wk	Screening time saved for subsequent device Quals.
BIP development and verification time	3 wks	1 wk	2 wks	Program modification instead of complete redevelopment.
Total Cycle Time Saved/Qualification			17 Wks	

## UBIBs: Advantages - 1

### Faster Turn-around Times

- Eliminates Re-fabrication
- Eliminates Redesign
- Eliminates Re-development
- Provides Faster BIP Development
- Provides Faster Verification Time



## UBIBs: Advantages - 2

### Better Utilization of Burn-In Ovens:

- **Flexibility on different systems:** Different versions from same OEM
- **More Availability of Ovens:** Early stress start on either of systems.
- **Lesser Waiting Time:** for the lot to stress and complete.
- **Faster Qual. cycle time** → Faster feedback to Process/Customers.

## Operational Advantages

**Operational Advantages:** As only one set of boards in operation:

- **Easier Operation:** no confusion to operators, on which boards to use.
- **Less Errors:** in using boards for each device.
- **Better Control** and monitoring of boards.
- **Easier to Manage** Boards, lesser storage space etc.,
- **Lesser Maintenance:** Only one set of boards to upkeep.
- **Lower Operational Costs → More savings.**

## Conclusion

- Cost of dedicated BIBs is significantly high.
- Common / UBIBs can be designed for >2 devices.
  - After meeting pre-requisites and with early design planning.
- UBIB design techniques & methods provide flexibility.
- UBIBs have several advantages when implemented.
- Implementation done: \$0.5~0.75M savings achieved.

## References

- 1) **JESD22A-108**: Temperature, Bias, and Operating Life Test specification by JEDEC, Solid State Technology Association.
- 2) **JESD-47**: Stress-Test-Driven Qualification of Integrated Circuits by JEDEC, Solid State Technology Association.
- 3) **JP-001**: Foundry Process Qualification Guidelines for Wafer Fabrication Manufacturing Sites, by JEDEC.
- 4) **JESD659**: Failure-Mechanism-Driven Reliability Monitoring, Electronics Industries Alliance, JEDEC, Solid State Technology Association.